

# M40Z300 M40Z300W

## 5 V or 3 V NVRAM supervisor for up to 8 LPSRAMs

Not recommended for new design

#### **Features**

- Converts low power SRAM into NVRAMs
- Precision power monitoring and power switching circuitry
- Automatic WRITE-protection when V<sub>CC</sub> is outof-tolerance
- Two-input decoder allows control for up to 8 SRAMs (with 2 devices active in parallel)
- Choice of supply voltages and power-fail deselect voltages:
  - M40Z300:

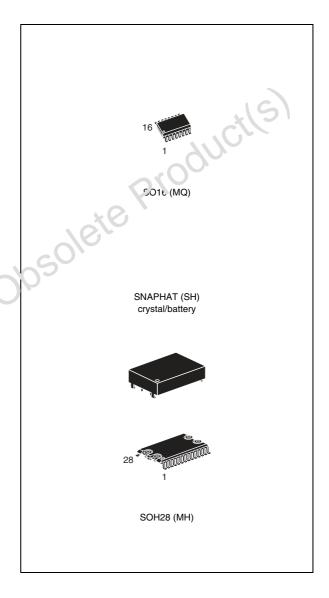
 $V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$ THS =  $V_{SS}$ : 4.5 V  $\leq$   $V_{PFD} \leq$  4.75 V THS =  $V_{OUT}$ : 4.2 V  $\leq V_{PFD} \leq$  4.5 V

M40Z300W:

 $V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$ 

THS =  $V_{SS}$ : 2.8 V  $\leq$   $V_{PFD} \leq$  3.0 V  $V_{CC}$  = 2.7 V to 3.3 V THS =  $V_{OUT}$ : 2.5 V  $\leq$   $V_{PFD} \leq$  2.7 V

- Reset output (RST) for power on reset
- Battery low pin (BL)
- Less than 12 ns thip enable access propagation relay (for 5.0 V device)
- Packaging includes a 28-lead SOIC and SN'Arr' A re top (to be ordered separately), or .^. 16-lead SOIC
- SOIC package provides direct connection for a SNAPHAT top which contains the battery
- RoHS compliant
  - Lead-free second level interconnect



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M40Z300, M40Z300W Description

#### 1 **Description**

The M40Z300/W NVRAM supervisor is a self-contained device which converts a standard low-power SRAM into a non-volatile memory. A precision voltage reference and comparator monitors the V<sub>CC</sub> input for an out-of-tolerance condition.

When an invalid  $V_{CC}$  condition occurs, the conditioned chip enable outputs ( $\overline{E1}_{CON}$  to E4<sub>CON</sub>) are forced inactive to write-protect the stored data in the SRAM. During a power failure, the SRAM is switched from the V<sub>CC</sub> pin to the lithium cell within the SNAPHAT® to provide the energy required for data retention. On a subsequent power-up, the SRAM remains write protected until a valid power condition returns.

The 28-pin, 330 mil SOIC provides sockets with gold plated contacts for direct connection to a separate SNAPHAT housing containing the battery. The SNAPHAT housing has not plated pins which mate with the sockets, ensuring reliable connection. The housing is keyed to prevent improper insertion. This unique design allows the SNAPHAT battery package to be mounted on top of the SOIC package after the completion of the surice mount process which greatly reduces the board manufacturing process complexity of either directly soldering or inserting a battery into a soldered holder. Providing non-volatility becomes a "SNAP." The 16-pin SOIC provides battery pins for an external user-supplied battery.

Insertion of the SNAPHAT housing after reflow prevents potential battery damage due to the high temperatures required for device surface-mounting. The SNAPHAT housing is also keyed to prevent reverse insertion.

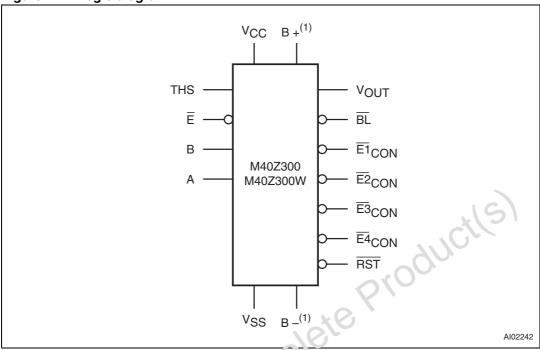
The 28-pin SOIC and battery packages are snipped separately in plastic anti-static tubes or in tape & reel form. For the 28-lead SCIC, the battery/crystal package (e.g., SNAPHAT) part number is "M4ZXX-BR00SH".

Caution:

Do not place the SNAPHAT battery top in conductive foam, as this will drain the lithium Josolete Produ button-cell battery.

Description M40Z300, M40Z300W

Figure 1. Logic diagram



1. For 16-pin SOIC package only.

Table 1. Signal names

	THS	Threshold select input
	Ē ,,(S)	Chip enable input
	E1 <sub>CON</sub> - E4 <sub>CON</sub>	Conditioned chip enable output
	A, B	Decoder inputs
	RST	Reset output (open drain)
	<u>RI</u>	Battery low output (open drain)
10	V <sub>OUT</sub>	Supply voltage output
cOlle	V <sub>CC</sub>	Supply voltage
000	$V_{SS}$	Ground
0	B +	Positive battery pin
	B –	Negative battery pin <sup>(1)</sup>
	NC	Not connected internally

<sup>1.</sup> For M40Z300W, B– must be connected to the negative battery terminal only (not to pin 8,  $V_{SS}$ ).

M40Z300, M40Z300W Description

Figure 2. 28-pin SOIC connections

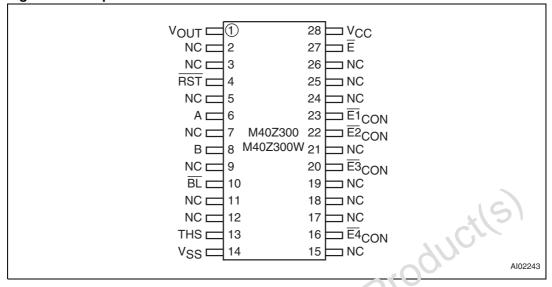


Figure 3. M40Z300 16-pin SOIC connections

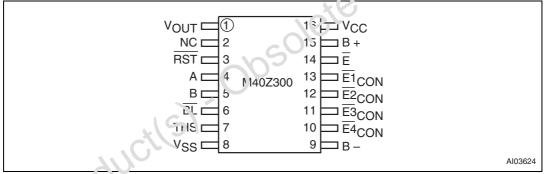
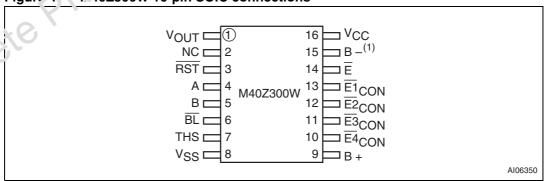


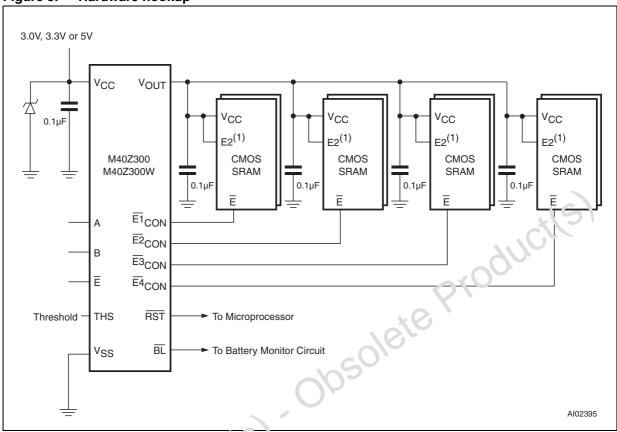
Figure 4 M40Z300W 16-pin SOIC connections



1. For M40Z300W, B– must be connected to the negative battery terminal only (not to pin 8,  $V_{SS}$ ).

Description M40Z300, M40Z300W

Figure 5. Hardware hookup



1. If the second chip enable pin (E2) is unused, it should be tied to V<sub>OUT</sub>.

M40Z300, M40Z300W Operation

### 2 Operation

The M40Z300/W, as shown in *Figure 5 on page 8*, can control up to four (eight, if placed in parallel) standard low-power SRAMs. These SRAMs must be configured to have the chip enable input disable all other input signals. Most slow, low-power SRAMs are configured like this, however many fast SRAMs are not. During normal operating conditions, the conditioned chip enable ( $\overline{\text{E1}}_{\text{CON}}$ ) to  $\overline{\text{E4}}_{\text{CON}}$ ) output pins follow the chip enable ( $\overline{\text{E}}$ ) input pin with timing shown in *Figure 6 on page 10* and *Table 7 on page 17*. An internal switch connects  $V_{\text{CC}}$  to  $V_{\text{OUT}}$ . This switch has a voltage drop of less than 0.3V ( $I_{\text{OUT1}}$ ).

When  $V_{CC}$  degrades during a power failure,  $\overline{E1}_{CON}$  to  $\overline{E4}_{CON}$  are forced inactive independent of  $\overline{E}$ . In this situation, the SRAM is unconditionally write protected as  $V_{CC}$  falls below an out-of-tolerance threshold ( $V_{PFD}$ ). For the M40Z300 the power fail detection value associated with  $V_{PFD}$  is selected by the Threshold Select (THS) pin and is shown in *Table 6 on page 15*).

Note: In either case, THS pin must be connected to either  $V_{SS}$  or  $V_{OUT}$ .

If chip enable access is in progress during a power fail detection, that memory cycle continues to completion before the memory is write protected. If the memory cycle is not terminated within time  $t_{WPT}$ ,  $\overline{E1}_{CON}$  to  $\overline{E4}_{CON}$  are unconditionally driven high, write protecting the SRAM. A power failure during a WPT  $\overline{E}$  cycle may corrupt data at the currently addressed location, but does not jeopardize the rest of the SRAM's contents. At voltages below  $V_{PFD}$  (min), the user can the absured the memory will be write protected within the Write Protect Time ( $t_{WPT}$ )  $\mu$  rovided the  $V_{CC}$  fall time exceeds  $t_F$  (see Figure 6 on page 10).

As  $V_{CC}$  continues to degrad  $\cdot$  the internal switch disconnects  $V_{CC}$  and connects the internal battery to  $V_{OUT}$ . This occurs at the switchover voltage ( $V_{SO}$ ). Below the  $V_{SO}$ , the battery provides a voltage  $V_{OUT}$  to the SRAM and can supply current  $I_{OUT2}$  (see *Table 6 on page 15*).

When  $V_{CC}$  rices above  $V_{SO}$ ,  $V_{OUT}$  is switched back to the supply voltage. Outputs  $\overline{E1}_{CON}$  to  $\overline{E4}_{CON}$  are held inactive for  $t_{CER}$  (120ms maximum) after the power supply has reached  $V_{FED}$  independent of the  $\overline{E}$  input, to allow for processor stabilization (see *Figure 10 on page 16*).

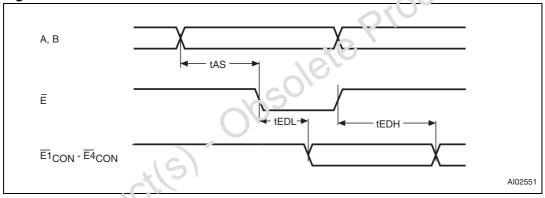
#### 2.1 Two to four decode

The M40Z300/W includes a 2 input (A, B) decoder which allows the control of up to 4 independent SRAMs. The truth table for these inputs is shown in *Table 2*.

Table 2. Truth table

	Inputs		Outputs				
Ē	В	Α	E1 <sub>CON</sub>	E2 <sub>CON</sub>	E3 <sub>CON</sub>	E4 <sub>CON</sub>	
Н	Х	Х	Н	Н	Н	Н	
L	L	L	L	Н	Н	Н	
L	L	Н	Н	L	Н	H	
L	Н	L	Н	Н	L	CH	
L	Н	Н	Н	Н	Н	Ĺ	

Figure 6. Address-decode time



Note:

During system design, compliance with the SRAM timing parameters must comprehend the propagation decay between  $\overline{E1}_{CON}$  -  $\overline{E4}_{CON}$ .

#### 2.2 Data retention lifetime calculation

Most low power SRAMs on the market today can be used with the M40Z300/W NVRAM SUPERVISOR. There are, however some criteria which should be used in making the final choice of which SRAM to use. The SRAM must be designed in a way where the chip enable input disables all other inputs to the SRAM. This allows inputs to the M40Z300/W and SRAMs to be "Don't Care" once  $V_{CC}$  falls below  $V_{PFD}(min)$ . The SRAM should also guarantee data retention down to  $V_{CC} = 2.0$  V. The chip enable access time must be sufficient to meet the system needs with the chip enable propagation delays included. If the SRAM includes a second chip enable pin  $(\overline{E2})$ , this pin should be tied to  $V_{OUT}$ .

If data retention lifetime is a critical parameter for the system, it is important to review the data retention current specifications for the particular SRAMs being evaluated. Most SRAMs specify a data retention current at 3.0 V. Manufacturers generally specify a typical condition for room temperature along with a worst case condition (generally at elevated temperatures). The system level requirements will determine the choice of which value to use.

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M40Z300, M40Z300W Operation

The data retention current value of the SRAMs can then be added to the I<sub>BAT</sub> value of the M40Z300/W to determine the total current requirements for data retention. The available battery capacity for the SNAPHAT<sup>®</sup> of your choice can then be divided by this current to determine the amount of data retention available (see *Table 13 on page 23*).

Caution:

Take care to avoid inadvertent discharge through  $V_{OUT}$  and  $\overline{E1}_{CON}$  -  $\overline{E4}_{CON}$  after battery has been attached.

For a further more detailed review of lifetime calculations, please see application note AN1012.

### 2.3 Power-on reset output

All microprocessors have a reset input which forces them to a known state when starting. The M40Z300/W has a reset output ( $\overline{RST}$ ) pin which is guaranteed to be low with in  $t_{WPT}$  of  $V_{PFD}$  (see *Table 7*). This signal is an open drain configuration. An appropriate pull-up resistor should be chosen to control the rise time. This signal will be valid for all voltage conditions, even when  $V_{CC}$  equals  $V_{SS}$ .

Once  $V_{CC}$  exceeds the power failure detect voltage  $V_{PFD}$ , an internal timer keeps  $\overline{RST}$  low for  $t_{REC}$  to allow the power supply to stabilize.

### 2.4 Battery low pin

The M40Z300/W automatically performs 'battery voltage monitoring upon power-up, and at factory-programmed time intervals of at least 24 hours. The battery low (BL) pin will be asserted if the battery voltage is found to be less than approximately 2.5 V. The BL pin will remain asserted until complexion of battery replacement and subsequent battery low monitoring tests, either during the next power-up sequence or the next scheduled 24-hour interval.

If a battery low is generated during a power-up sequence, this indicates that the battery is below 2.5 V and may not be able to maintain data integrity in the SRAM. Data should be considered suspect, and verified as correct. A fresh battery should be installed.

 $\it X$  c pattery low indication is generated during the 24-hour interval check, this indicates that the battery is near end of life. However, data is not compromised due to the fact that a nominal  $V_{CC}$  is supplied. In order to insure data integrity during subsequent periods of battery backup mode, the battery should be replaced. The SNAPHAT top should be replaced with valid  $V_{CC}$  applied to the device.

The M40Z300/W only monitors the battery when a nominal  $V_{CC}$  is applied to the device. Thus appli-cations which require extensive durations in the battery backup mode should be powered-up periodically (at least once every few months) in order for this technique to be beneficial. Additionally, if a battery low is indicated, data integrity should be verified upon power-up via a checksum or other technique. The  $\overline{BL}$  pin is an open drain output and an appropriate pull-up resistor to  $V_{CC}$  should be chosen to control the rise time.

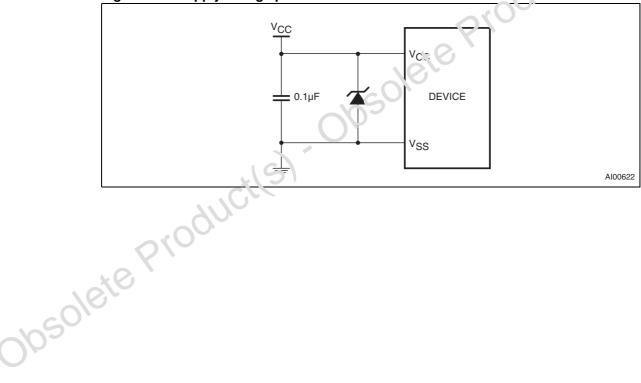
Operation M40Z300, M40Z300W

### 2.5 V<sub>CC</sub> noise and negative going transients

 $I_{CC}$  transients, including those produced by output switching, can produce voltage fluctuations, resulting in spikes on the  $V_{CC}$  bus. These transients can be reduced if capacitors are used to store energy which stabilizes the  $V_{CC}$  bus. The energy stored in the bypass capacitors will be released as low going spikes are generated or energy will be absorbed when overshoots occur. A ceramic bypass capacitor value of 0.1  $\mu$ F (as shown in *Figure 7*) is recommended in order to provide the needed filtering.

In addition to transients that are caused by normal SRAM operation, power cycling can generate negative voltage spikes on  $V_{CC}$  that drive it to values below  $V_{SS}$  by as much as one volt. These negative spikes can cause data corruption in the SRAM while in battery backup mode. To protect from these voltage spikes, STMicroelectronics recommends connecting a Schottky diode from  $V_{CC}$  to  $V_{SS}$  (cathode connected to  $V_{CC}$ , anode to  $\tilde{v}_{CS}$ ). Schottky diode 1N5817 is recommended for through hole and MBRS120T3 is recommended for surface mount.

Figure 7. Supply voltage protection



M40Z300, M40Z300W Maximum ratings

## 3 Maximum ratings

Stressing the device above the rating listed in the absolute maximum ratings table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 3. Absolute maximum ratings

Symbol	Parameter	Value	Unit	
т	Ambient operating temperature	Grade 1	0 to 70	°C
T <sub>A</sub>	Ambient operating temperature	Grade 6	-40 to 85	C
т	Storage temperature	SNAPHAT <sup>®</sup>	−40 tc ∞5	°C
T <sub>STG</sub>	Storage temperature	SOIC	– ₹5 to 125	°C
T <sub>SLD</sub> <sup>(1)</sup>	Lead solder temperature for 10 sec	onds	260	°C
V <sub>IO</sub>	Input or output voltage		$-0.3$ to $V_{CC} + 0.3$	V
V	Supply voltage	M407300	-0.3 to 7.0	V
V <sub>CC</sub>	Supply voltage	[//40≥300W	-0.3 to 4.6	V
Io	Output current	0,	20	mA
$P_{D}$	Power dissipation		1	W

For SO package, Lead-free (Pb-free) lead inish. Reflow at peak temperature of 260°C (total thermal budget not to exceed 245°C for greater than 30 seconds).

Caution: Negative undershoots below -0.3 V are not allowed on any pin while in the battery backup

mode.

Caution: Do NOT wave sclcler SOIC to avoid damaging SNAPHAT sockets.

### 4 DC and AC parameters

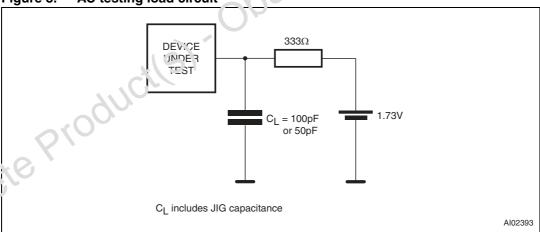
This section summarizes the operating and measurement conditions, as well as the DC and AC characteristics of the device. The parameters in the following DC and AC characteristic tables are derived from tests performed under the measurement conditions listed in *Table 4:* DC and AC measurement conditions. Designers should check that the operating conditions in their projects match the measurement conditions when using the quoted parameters.

Table 4. DC and AC measurement conditions

Parameter	M40Z300	M40Z300W	
V <sub>CC</sub> supply voltage		4.5 to 5.5 V	2.7 to 3.6 V
Ambient operating temperature	Grade 1	0 to 70 °C	0 tc 70 °C
Ambient operating temperature	Grade 6	–40 to 85 °C	–40 დ 85 °C
Load capacitance (C <sub>L</sub> )		100 pF	50 pF
Input rise and fall times		≤ 5 n 3	≤ 5 ns
Input pulse voltages		0 to 3 V	0 to 3 V
Input and output timing ref. voltages	×0	1.5 V	1.5 V

Note: Output High Z is defined as the point where data is 1.0 onger driven.

Figure 8. AC testing load circuit



Note: 50 pF for M40Z300W.

Table 5. Capacitance

Symbol	Parameter <sup>(1)(2)</sup>	Min	Max	Unit
C <sub>IN</sub>	Input capacitance	-	8	pF
C <sub>OUT</sub> (3)	Input/output capacitance	-	10	pF

- 1. Sampled only, not 100% tested.
- 2. At 25 °C, f = 1 MHz.
- 3. Outputs deselected.

Table 6. DC characteristics

Cum	Davameter	Parameter Test condition <sup>(1)</sup>		M40Z300			M40Z300W		
Sym	Parameter	rest condition 7	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>LI</sub> <sup>(2)</sup>	Input leakage current	$0 \text{ V} \leq V_{IN} \leq V_{CC}$			±1			±1	μΑ
I <sub>CC</sub>	Supply current	Outputs open		3	6		2	4	mA
V <sub>IL</sub>	Input low voltage		-0.3		0.8	-0.3		0.8	V
V <sub>IH</sub>	Input high voltage		2.2		V <sub>CC</sub> + 0.3	2.0		V <sub>CC</sub> + 0.3	V
	Output low voltage	I <sub>OL</sub> = 4.0 mA			0.4			0.4	V
V <sub>OL</sub>	Output low voltage (open drain) <sup>(3)</sup>	I <sub>OL</sub> = 10 mA			0.4			0.4	V
V <sub>OH</sub>	Output high voltage	$I_{OH} = -2.0 \text{ mA}$	2.4			2.4		10	V
V <sub>OHB</sub>	V <sub>OH</sub> battery backup <sup>(4)</sup>	$I_{OUT2} = -1.0 \mu A$	2.0	2.9	3.6	2.0	2.9	3.0	V
1.	V <sub>OUT</sub> current (active)	$V_{OUT} > V_{CC} - 0.3$			250		2	150	mA
I <sub>OUT1</sub>	V <sub>OUT</sub> current (active)	$V_{OUT} > V_{CC} - 0.2$			150			100	mA
I <sub>OUT2</sub>	V <sub>OUT</sub> current (battery backup)	$V_{OUT} > V_{BAT} - 0.3$		100		6/	100		μΑ
I <sub>CCDR</sub>	Data retention mode current <sup>(5)</sup>				11:00			100	nA
THS	Threshold select voltage		V <sub>SS</sub>	5	V <sub>OUT</sub>	V <sub>SS</sub>		V <sub>OUT</sub>	V
V	Power-fail deselect voltage (THS = V <sub>SS</sub> )		4.5	4.6	4.75	2.8	2.9	3.0	V
V <sub>PFD</sub>	Power-fail deselect voltage (THS = V <sub>OUT</sub> )	4(5)	4.2	4.35	4.5	2.5	2.6	2.7	V
V <sub>SO</sub>	Battery backup switchover voltage	1000		3.0			2.5		V
$V_{BAT}$	Battery voltage		2.0	2.9	3.6	2.0	2.9	3.6	V

<sup>1.</sup> Valid for ambient ope ating temperature:  $T_A = 0$  to 70 °C or -40 to 85 °C;  $V_{CC} = 2.7$  to 3.6 V or 4.5 to 5.5 V (except where noted).

- 2. Outputs done lected.
- 3. For  $\overline{\square S}$   $\overline{\square}$   $\overline{\square}$   $\overline{\square}$   $\overline{\square}$  pins (open drain).
- 4. Chip anable outputs  $(\overline{E1}_{CON} \overline{E4}_{CON})$  can only sustain CMOS leakage currents in the battery backup mode. Higher leakage currents will reduce battery life.
- 5. Measured with  $V_{OUT}$  and  $\overline{E1}_{CON}$   $\overline{E4}_{CON}$  open.

Figure 9. Power-down timing

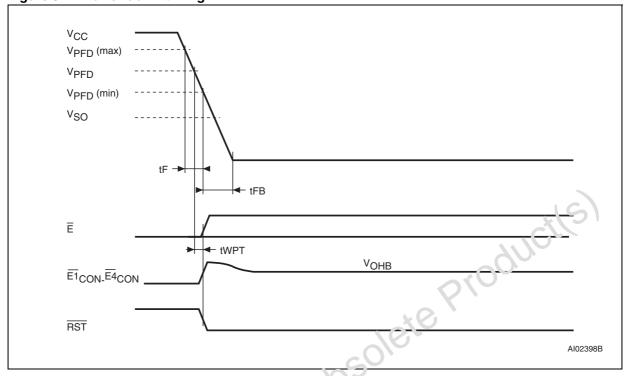


Figure 10. Power-up timing

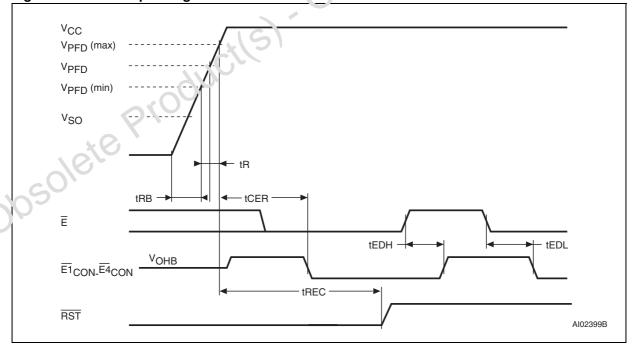


Table 7. Power down/up mode AC characteristics

Symbol	Parameter <sup>(1)</sup>		Min	Max	Unit
t <sub>F</sub> <sup>(2)</sup>	$V_{PFD}$ (max) to $V_{PFD}$ (min) $V_{CC}$ fall time		300		μs
t <sub>FB</sub> <sup>(3)</sup>	V <sub>PED</sub> (min) to V <sub>SS</sub> V <sub>CC</sub> fall time	M40Z300	10		μs
YFB T	Aben (Illin) to ASS ACC ian mile	M40Z300W	150		μs
t <sub>R</sub>	$V_{PFD}$ (min) to $V_{PFD}$ (max) $V_{CC}$ rise time		10		μs
t	Chip enable propagation delay low	M40Z300		12	ns
'EDL	t <sub>EDL</sub> Chip enable propagation delay low			20	ns
t	Chip enable propagation delay high	M40Z300		10	ns
t <sub>EDH</sub>	Crip enable propagation delay riigh	M40Z300W		20	ns
t <sub>AS</sub>	A, B set up to E		0	. (	r.s
t <sub>CER</sub>	Chip enable recovery		40	130	ms
t <sub>REC</sub> <sup>(4)</sup>	V <sub>PFD</sub> (max) to RST high		40	120	ms
t=	Write protect time	M40Z300	45	150	μs
t <sub>WPT</sub>	write protect time	M40Z300W	40	250	μs
t <sub>RB</sub>	V <sub>SS</sub> to V <sub>PFD</sub> (min) V <sub>CC</sub> rise time	0.	1		μs

<sup>1.</sup> Valid for ambient operating temperature:  $T_A = 0$  to 70 °C c\* - 40 to 9 5°C;  $V_{CC} = 2.7$  to 3.6 V or 4.5 to 5.5 V(except where noted).

<sup>2.</sup>  $V_{PFD}$  (max) to  $V_{PFD}$  (min) fall time of less than  $t_F$  mey recult in deselection/write protection not occurring until 200  $\mu s$  after  $V_{CC}$  passes  $V_{PFD}$  (min).

<sup>3.</sup>  $\rm \ V_{PFD}$  (min) to  $\rm \ V_{SS}$  fall time of less than  $\rm t_{FB}$  may cause corruption of RAM data.

<sup>4.</sup> t<sub>REC</sub> (min) = 20ms for industrial temperature Grade 6 device.

## 5 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.



Figure 11. SOH28 – 28-lead plastic small outline, 4-socket battery SNAPHAT, package outline

Table 8. SOH28 – 28-lead plastic small outline, battery SNAPHAT, package mechanical data

	Cumbal		mm		S	inches	
	Symbol	Тур	Min	Max	Тур	Min	Max
	Α			3.05			0.120
	A1		0.05	0.36		0.002	0.014
	A2		2.34	2.69		0.092	0.106
	В	(C)	0.36	0.51		0.014	0.020
	С	20,0	0.15	0.32		0.006	0.012
	201		17.71	18.49		0.697	0.728
	E		8.23	8.89		0.324	0.350
10	е	1.27	-	_	0.050	_	-
c0//c	eB		3.20	3.61		0.126	0.142
0050°	Н		11.51	12.70		0.453	0.500
OF	L		0.41	1.27		0.016	0.050
	а		0°	8°		0°	8°
	N		28			28	
	СР			0.10			0.004

Figure 12. SH – 4-pin SNAPHAT housing for 48 mAh battery, package outline

Table 9. SH – 4-pin SNAPHAT housing for 48 m/n battery, package mechanical data

	Symbol -		mm	-0	0	inches	
		Тур	Min	Mex	Тур	Min	Max
	Α			9.78			0.385
	A1		5.73	7.24		0.265	0.285
	A2		3.48	6.99		0.255	0.275
	A3	. (C)		0.38			0.015
	В	70.	0.46	0.56		0.018	0.022
	D	2	21.21	21.84		0.835	0.860
	E.		14.22	14.99		0.560	0.590
	эA		15.55	15.95		0.612	0.628
7/6	eB		3.20	3.61		0.126	0.142
, c0,	L		2.03	2.29		0.080	0.090
262							

Figure 13. SH – 4-pin SNAPHAT housing for 120mAh battery, package outline

Table 10. SH – 4-pin SNAPHAT housing for 120 m4h sattery, package mechanical data

	Symbol	mm			0	inches		
		Тур	Min	Toler.	Тур	Min	Max	
	А			10.54			0.415	
	A1		৭.00	8.51		0.315	.0335	
	A2		724	8.00		0.285	0.315	
	A3	(C)		0.38			0.015	
	В	70,	0.46	0.56		0.018	0.022	
	D	200	21.21	21.84		0.835	0.860	
	F		17.27	18.03		0.680	0.710	
	эА		15.55	15.95		0.612	0.628	
76	eB		3.20	3.61		0.126	0.142	
c0'	L		2.03	2.29		0.080	0.090	
202								

Figure 14. SO16 – 16-lead plastic small outline, 150 mils body width, package outline

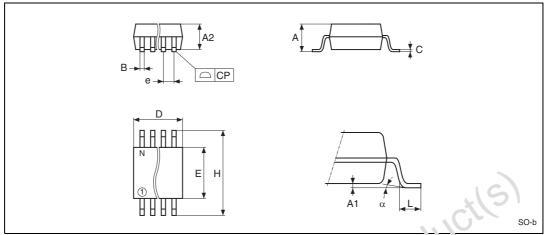


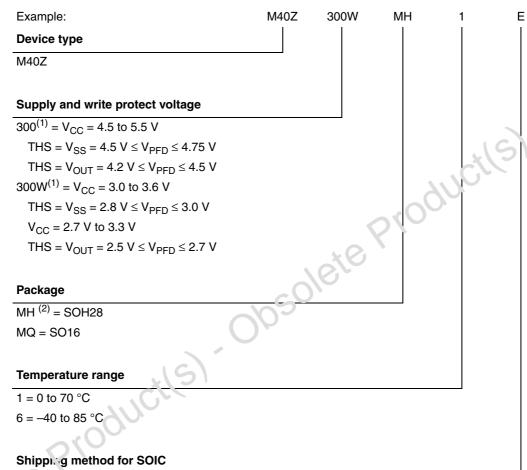
Table 11. SO16 – 16-lead plastic small outline, 150 mils body width, package mechanical data

	Symbol	mm			inches		
		Тур.	Min.	Max.	Тур.	Min.	Max.
	А			1.75			0.069
	A1		0.10	0.25		0.004	0.010
	A2		51	1.60			0.063
	В	(G/L)	0.35	0.46		0.014	0.018
	С	90,	0.19	0.25		0.007	0.010
	270		9.80	10.00		0.386	0.394
	F.		3.80	4.00		0.150	0.158
\ 0	е	1.27	_	_	0.050	_	_
-0/6	Н		5.80	6.20		0.228	0.244
205	L		0.40	1.27		0.016	0.050
Ob	а		0°	8°		0°	8°
	N		16			16	
	СР			0.10			0.004

M40Z300, M40Z300W Part numbering

## 6 Part numbering

Table 12. Ordering information example



- E Lead-free package (ECOPACK®), tubes
- F = Lead-free package (ECOPACK®), tape & reel
- 1. Not recommended for new design. Contact ST sales office for availability.
- 2. The SOIC package (SOH28) requires the battery package (SNAPHAT®) which is ordered separately under the part number "M4Zxx-BR00SH" in plastic tubes or "M4Zxx-BR00SHTR" in tape & reel form.

#### Caution:

Do not place the SNAPHAT battery package "M4Zxx-BR00SH" in conductive foam as it will drain the lithium button-cell battery.

For other options, or for more information on any aspect of this device, please contact the ST sales office nearest you

Table 13. SNAPHAT® battery table

Part number	Description	Package
M4Z28-BR00SH1	Lithium battery (48 mAh) SNAPHAT	SH
M4Z32-BR00SH1	Lithium battery (120 mAh) SNAPHAT	SH

# 7 Revision history

Table 14. Document revision history

Date	Revision	Changes
Mar-1999	1.0	First issue
08-Mar-2000	1.1	Document layout changed; SO16 package added; battery capacity changed ( <i>Table 13</i> )
22-Sep-2000	1.2	SO16 package measures change
23-Feb-2001	1.3	Added information for industrial temperature (Table 3, 7, 12)
30-May-2001	1.4	Change "Controller" references to "SUPERVISOR"
10-Jul-2001	2.0	Reformatted; added temp/voltage info. to tables ( <i>Table 6</i> , 7); Figures changed ( <i>Figure 1</i> , 3, 5, 8, 6)
01-Aug-2001	2.1	E2 connections added to hookup (Figure 5)
15-Jan-2002	2.2	16-pin SOIC connections split, graphic added (Figure 4); addition to hardware hookup (Figure 5)
13-May-2002	2.3	Modify reflow time and temperature fc otnote (Table 3)
31-Oct-2003	2.4	Update DC characteristics (Tahle 6)
04-Nov-2003	2.5	Correct DC characteristics (Table 6)
23-Feb-2005	3.0	Reformatted; IR reflect, SO package updates (Table 3)
05-Nov-2007	4.0	Reformatied; a died lead-free second level interconnect to cover page and Section 5. Package mechanical data; updated Figure 10 and Table 3, 12, 13.
19-Oct-2010	5	Devices not recommended for new design, updated document status; updated <i>Table 12</i> , ECOPACK® text in <i>Section 5: Package mechanical data</i> ; reformatted document.
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